

**Attachment No. 7**

**Committee B02.11  
Subcommittee on Electric Contact Test Methods  
Agenda  
Tuesday, May 8, 2007, 10:30am, ASTM Headquarters  
(Issue 1)**

- Reading of minutes
- Review of agenda
- Membership report (additions, inactive, drop listing)
- Review of ballot items
  1. B810 on test calibration by copper coupon mass gain.
  2. B542 terminology “crimp” definition
  3. B920 on porosity by the hypochlorite method.
  4. B735 on porosity (gold flash defined)
- Report on standards for review in 2007
  - B539-02e1 Standard Test Methods for Measuring Resistance of Electrical Connections (Static Contacts) Steve Cole
  - B773-96(2002)e1 Standard Guide for Ultrasonic C-Scan Bond Evaluation of Brazed or Welded Electrical Contact Assemblies (Ed Sproles will contact John Kuzmech for assignment of a reviewer)
  - B812-96(2002)e1 Standard Test Method for Resistance to Environmental Degradation of Electrical Pressure Connections Involving Aluminum and Intended for Residential Applications Jesse Aronstein
  - B825-02 Standard Test Method for Coulometric Reduction of Surface Films on Metallic Test Samples Simeon Krumbein
  - B868-96(2002)e3 Standard Practice for Contact Performance Classification of Electrical Connection Systems Jesse Aronstein
- Liaison report on progress on committee B1 work item on silver coated copper wire—Simeon Krumbein
- Staff report (Jeff Adkins) Next committee meeting, etc.
- New Business
- Schedule for next meeting